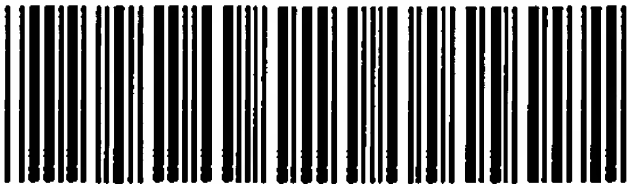


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/645,244	MEIER ET AL.	
	Examiner	Art Unit	
	Shih-Chao Chen	2821	

SEARCHED			
Class	Subclass	Date	Examiner
343	700MS, 702, 757, 848, 853, 893	3/3/2005	CHEN

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
343	700MS	3/7/2005	CHEN
343	757, 853	3/7/2005	CHEN

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST (See attached printout).	3/3/2005	CHEN